

ISO/IEC 10373-6:2025-02 (E)

Cards and security devices for personal identification - Test methods - Part 6: Contactless proximity objects

Contents

Page

- Foreword..... v
- 1 Scope..... 1**
- 2 Normative references..... 1**
- 3 Terms, definitions, symbols and abbreviated terms..... 1**
 - 3.1 Terms and definitions..... 1
 - 3.2 Symbols and abbreviated terms..... 2
- 4 Default items applicable to the test methods..... 5**
 - 4.1 Test environment..... 5
 - 4.2 Pre-conditioning..... 5
 - 4.3 Setup tolerances..... 5
 - 4.4 Spurious inductance..... 6
 - 4.5 Measurement uncertainty..... 6
 - 4.6 DUT position..... 6
 - 4.7 Test conditions for PCD..... 6
 - 4.8 Test conditions for PICC..... 7
- 5 Apparatus and circuits for test of ISO/IEC 14443-1 and ISO/IEC 14443-2 parameters..... 10**
 - 5.1 Overview..... 10
 - 5.2 Minimum requirements for measurement instruments — Oscilloscope..... 10
 - 5.3 Calibration coils..... 11
 - 5.3.1 General..... 11
 - 5.3.2 Size of the calibration coil card..... 11
 - 5.3.3 Thickness and material of the calibration coil card..... 11
 - 5.3.4 Coil characteristics..... 11
 - 5.4 Test PCD assemblies..... 12
 - 5.4.1 General..... 12
 - 5.4.2 Test PCD antennas..... 13
 - 5.4.3 Sense coils..... 13
 - 5.4.4 Mechanical construction of the Test PCD assemblies..... 14
 - 5.5 Reference PICC and Active Reference PICC..... 15
 - 5.5.1 General..... 15
 - 5.5.2 Reference PICC..... 15
 - 5.5.3 Active Reference PICC..... 18
 - 5.6 PICC transmission test setup..... 20
 - 5.6.1 General description..... 20
 - 5.6.2 Phase stability precondition test..... 20
 - 5.7 EMD test setup..... 21
 - 5.7.1 General description..... 21
 - 5.7.2 Computation of power versus time..... 21
 - 5.7.3 Noise floor precondition test..... 22
- 6 Test of ISO/IEC 14443-1 parameters..... 22**
 - 6.1 PCD test for alternating magnetic fields..... 22
 - 6.1.1 Purpose..... 22
 - 6.1.2 Procedure..... 23
 - 6.1.3 Test report..... 23
 - 6.2 PICC test for alternating magnetic fields..... 23
 - 6.2.1 Purpose..... 23
 - 6.2.2 Apparatus..... 23

6.2.3	Procedure	24
6.2.4	Test report	24
6.3	PXD tests	24
7	Test of ISO/IEC 14443-2 parameters	24
7.1	PCD tests	24
7.1.1	PCD field strength	25
7.1.2	Modulation index m and waveform	26
7.1.3	Phase stability test	27
7.1.4	Load modulation reception for PICC to PCD bit rates of $f_c/128$, $f_c/64$, $f_c/32$ and $f_c/16$	27
7.1.5	Load modulation reception for PICC to PCD bit rates of $f_c/8$, $f_c/4$ and $f_c/2$	34
7.1.6	PCD EMD immunity test	35
7.2	PICC tests	36
7.2.1	PICC transmission	36
7.2.2	PICC EMD level and low EMD time test	38
7.2.3	PICC reception	39
7.2.4	PICC resonance frequency	43
7.2.5	PICC maximum loading effect	43
7.2.6	PICC operating field strength test	45
7.3	Test methods for bit rates of $3f_c/4$, f_c , $3f_c/2$ and $2f_c$ from PCD to PICC	45
7.4	PXD tests	45
8	Test of ISO/IEC 14443-3 and ISO/IEC 14443-4 parameters	46
8.1	PCD tests	46
8.1.1	PCD EMD recovery test	46
8.1.2	Additional PCD tests	47
8.2	PICC tests	48
8.3	PXD tests	48
8.3.1	PCD and PICC Modes	48
8.3.2	Automatic mode alternation	48
8.3.3	PCD Mode	49
8.3.4	PICC Mode	50
Annex A (normative) Test PCD antennas		53
Annex B (normative) PICC Type A FDT determination method		60
Annex C (normative) Sense coils		63
Annex D (normative) Reference PICCs and Active Reference PICCs		66
Annex E (normative) PCD modulation index m and waveform analysis tool		78
Annex F (informative) Program for the evaluation of the load modulation amplitude		84
Annex G (normative) Additional PICC test methods		85
Annex H (normative) Additional PCD test methods		148
Annex I (normative) High bit rate selection test methods for PCD		192
Annex J (informative) Program for EMD level measurements		204
Annex K (normative) Test methods for bit rates of $3f_c/4$, f_c, $3f_c/2$ and $2f_c$ from PCD to PICC		205
Annex L (normative) Frame with error correction test methods		214
Annex M (normative) PCD phase stability analysis tool		223
Annex N (normative) PICC amplitude and phase drift analysis tool		225
Annex O (normative) Conformance test plan		232
Bibliography		240